

Assertion-Based Microarchitecture Design for Improved Fault Tolerance

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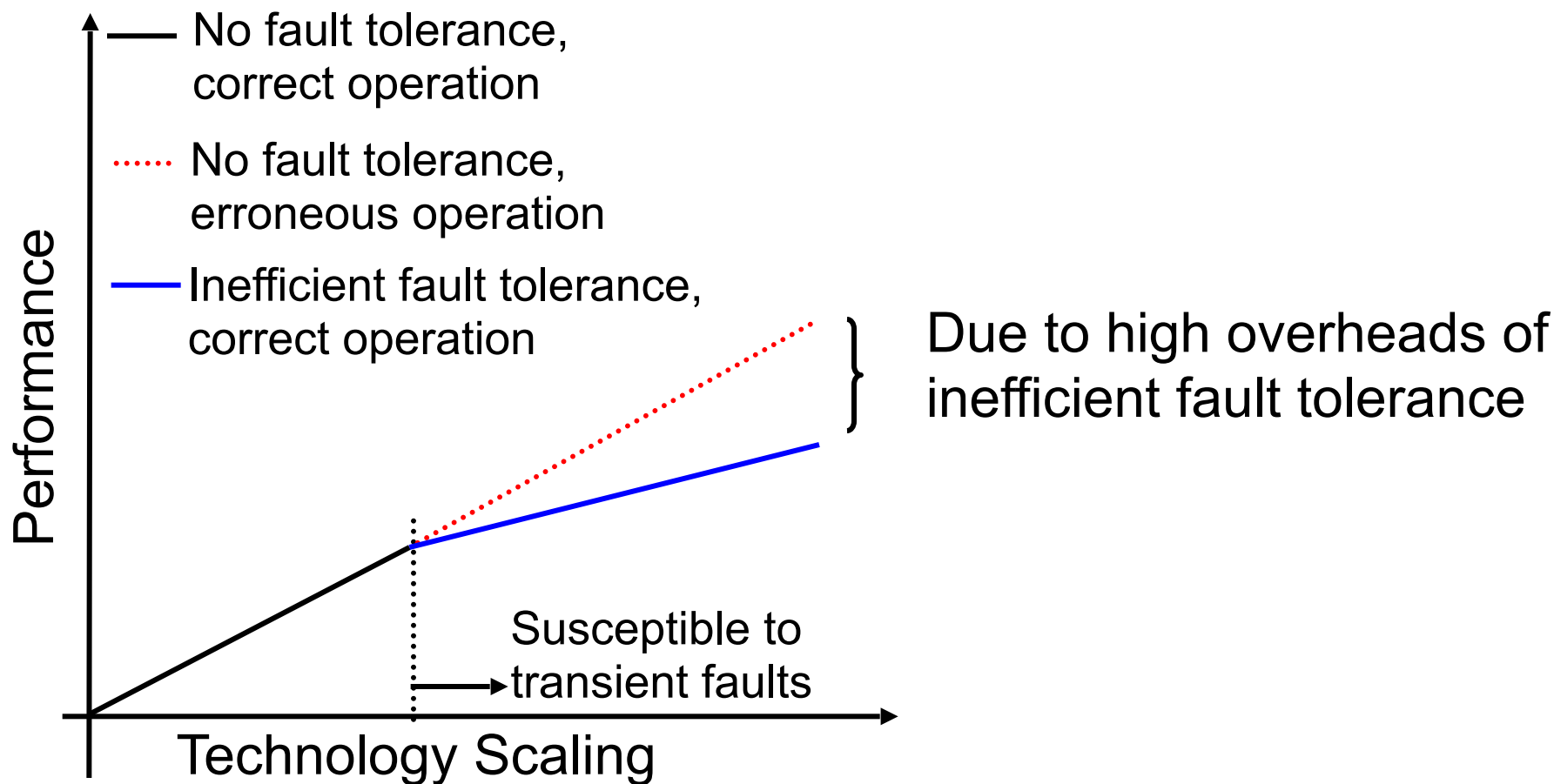


Center for Embedded Systems Research (CESR)
Department of Electrical & Computer Engineering
North Carolina State University

Motivation

- Technology scaling
 - Smaller, faster transistors
 - Transistors more susceptible to transient faults
- How to build reliable processors using unreliable transistors?

Motivation

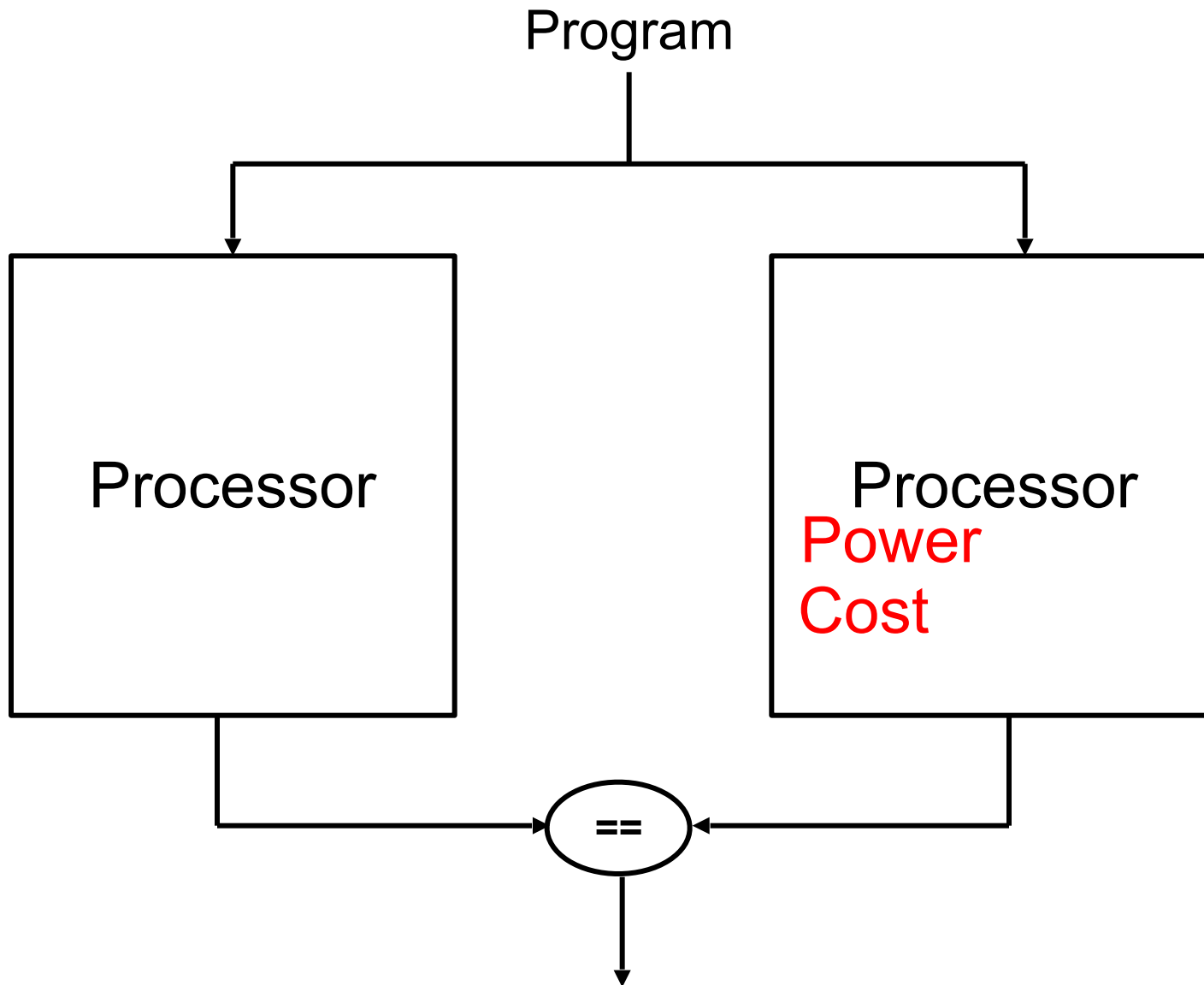


Need efficient fault tolerance solutions

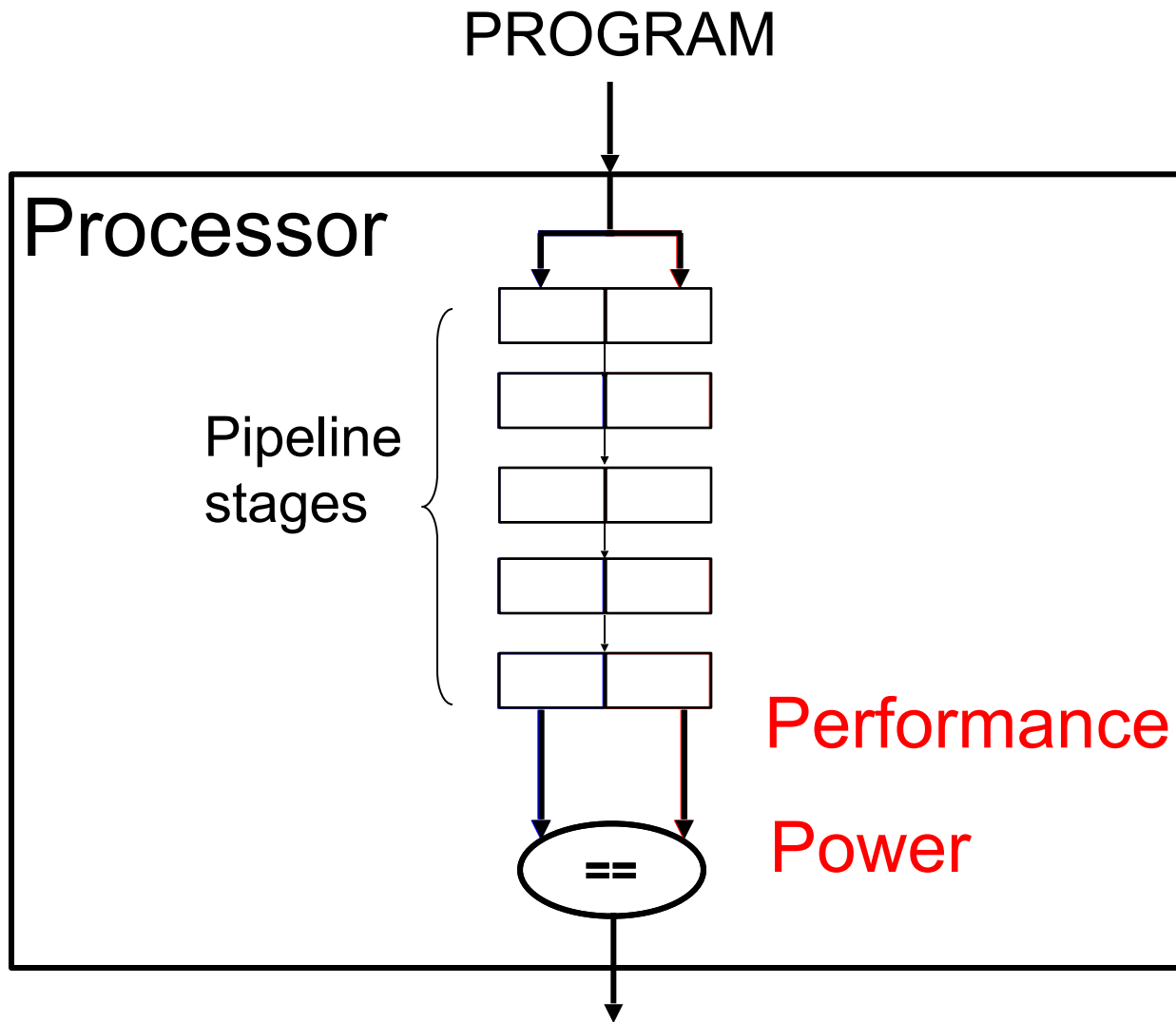
Redundant Multithreading (RMT)

- Duplicate a program and compare outcomes to detect transient faults
- Positives
 - Simple and straightforward
 - General solution
 - Complete fault coverage
- **Negatives**
 - High overhead

RMT using an extra processor



RMT using simultaneous multithreading



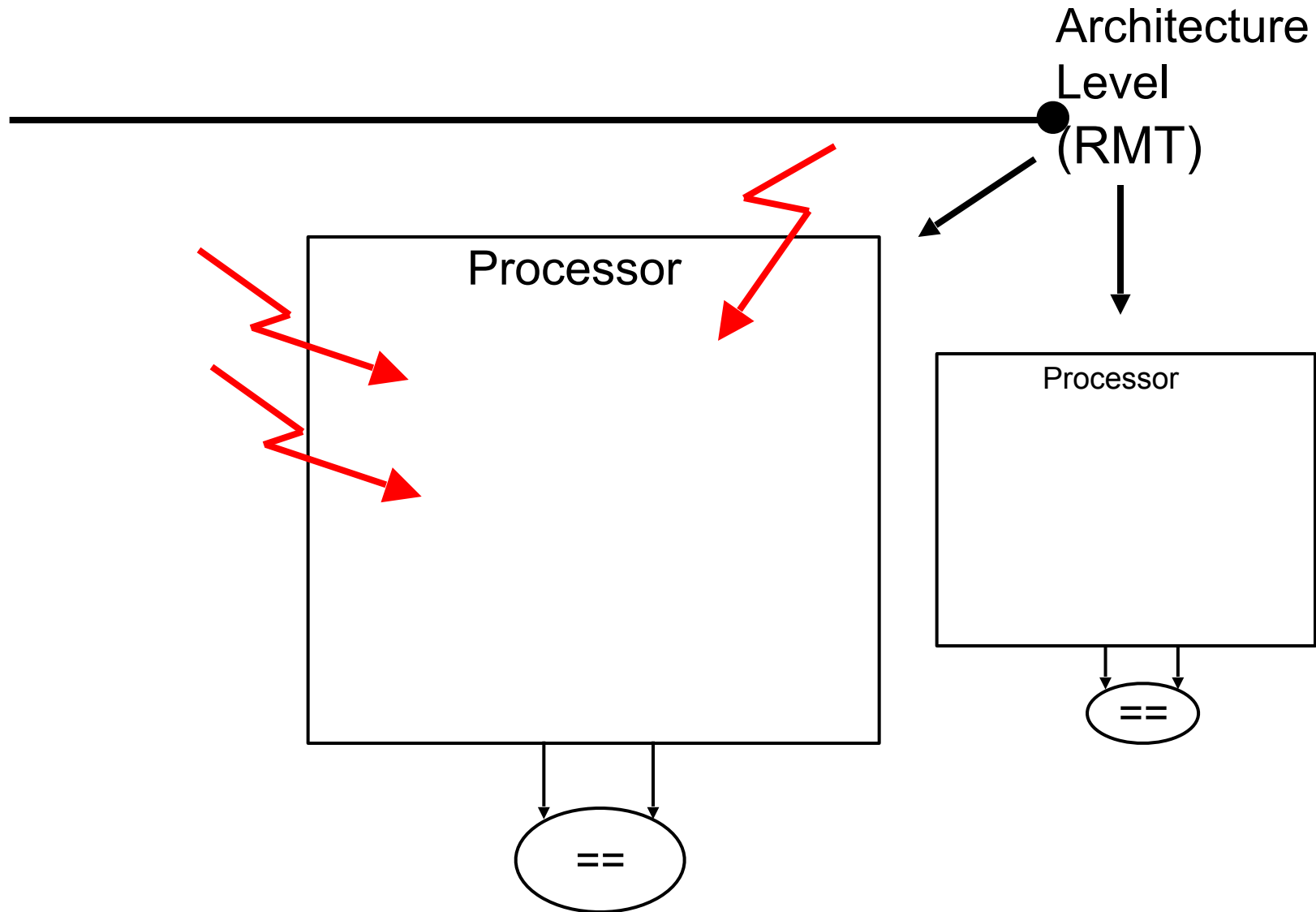
Alternate solution: Targeted fault checks

- Add regimen of fault checks
- Specific to logic block
 - Arbitrary latches: Robust latch design
 - Arbitrary gates: Self-checking logic
 - FSM: Self-checking FSM designs
 - ALU: Self-checking ALUs, RESO
 - Storage and buses: Parity, ECC
- Positives
 - No overhead of duplicating the program
- Negatives
 - Not general, i.e., many types of checks needed

Our contribution: Microarchitectural Assertions

- Novel class of fault checks
- Key Idea: Confirm μ arch. “truths” within processor pipeline
- Catch-all checks for microarchitecture mechanisms
- Positives
 - Broad coverage (catch-all checks)
 - Very low-overhead solution (no redundant execution)

Spectrum of fault checks



Spectrum of fault checks

Logic
Circuit
Level

Architecture
Level
(RMT)

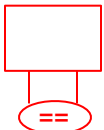
 robust
flip-flop



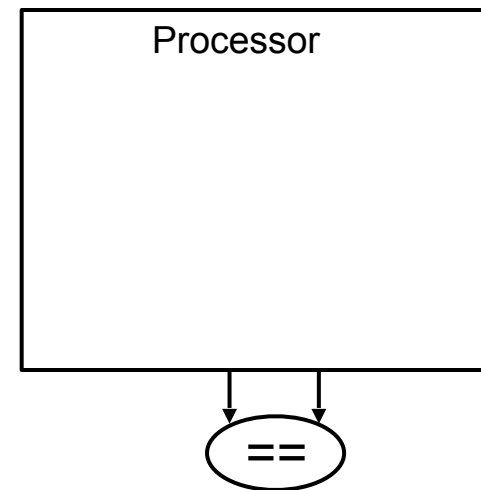
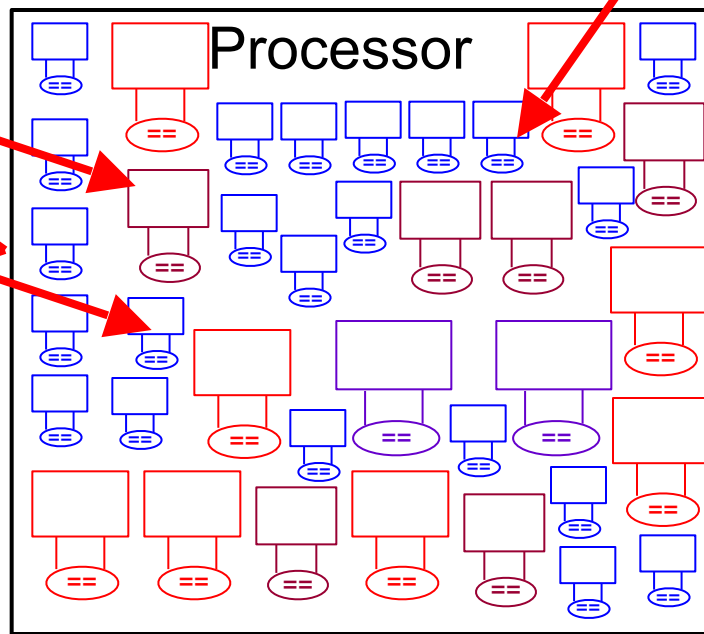
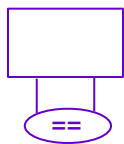
 self-check
FSM



 parity/ECC



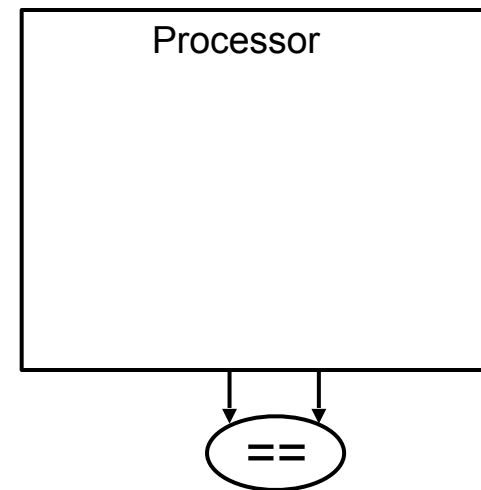
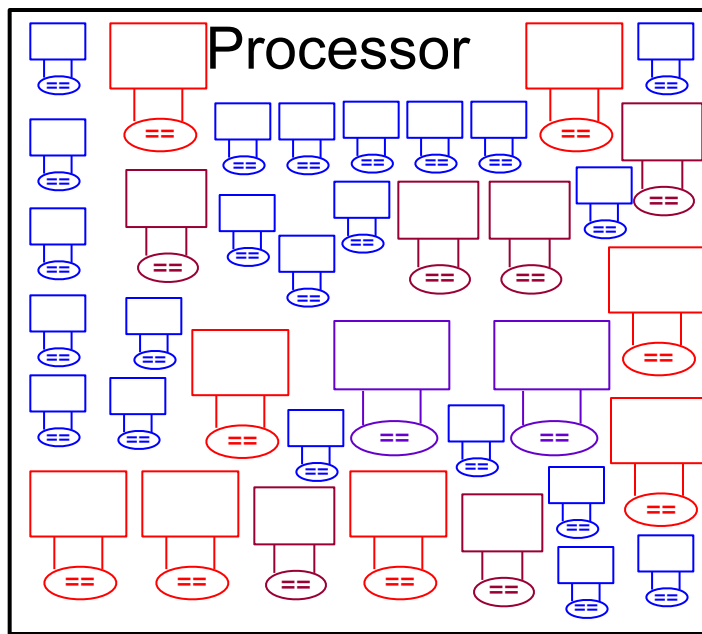
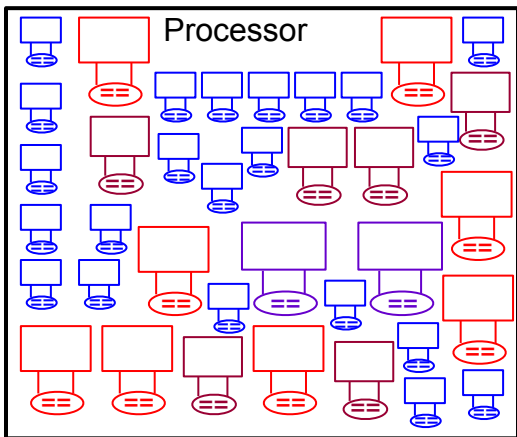
 self-check
ALU



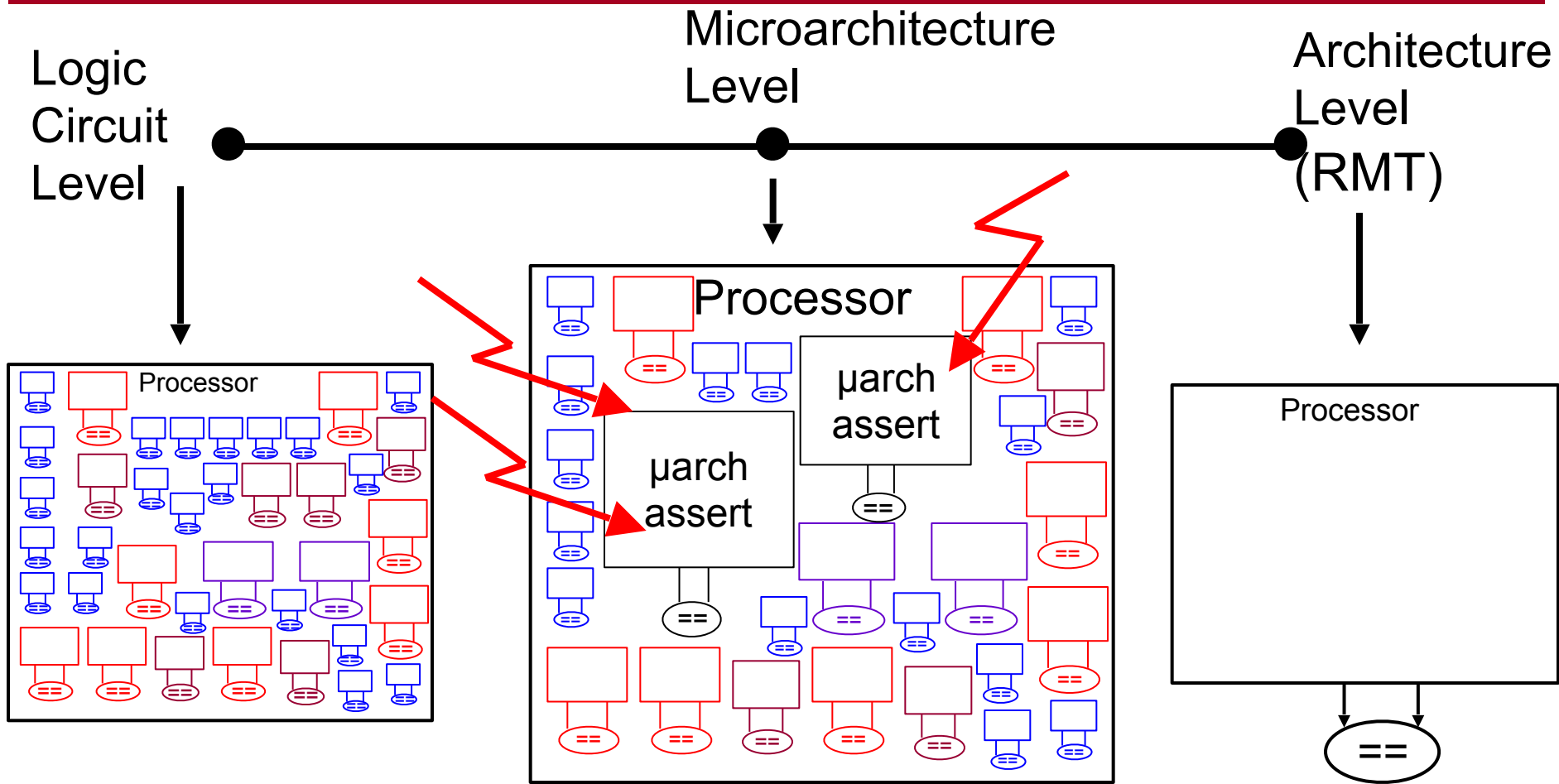
Spectrum of fault checks

Logic
Circuit
Level

Architecture
Level
(RMT)

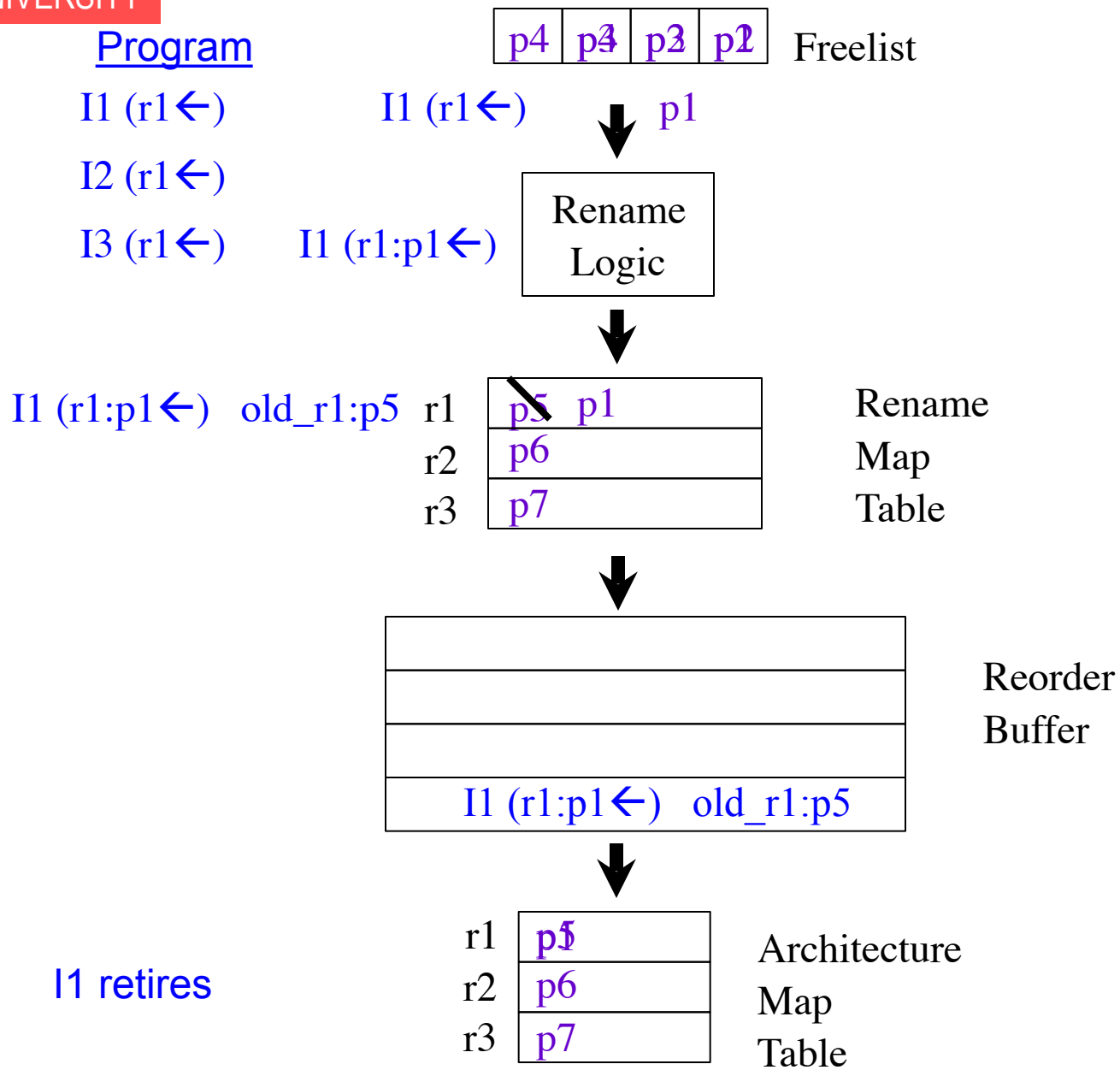


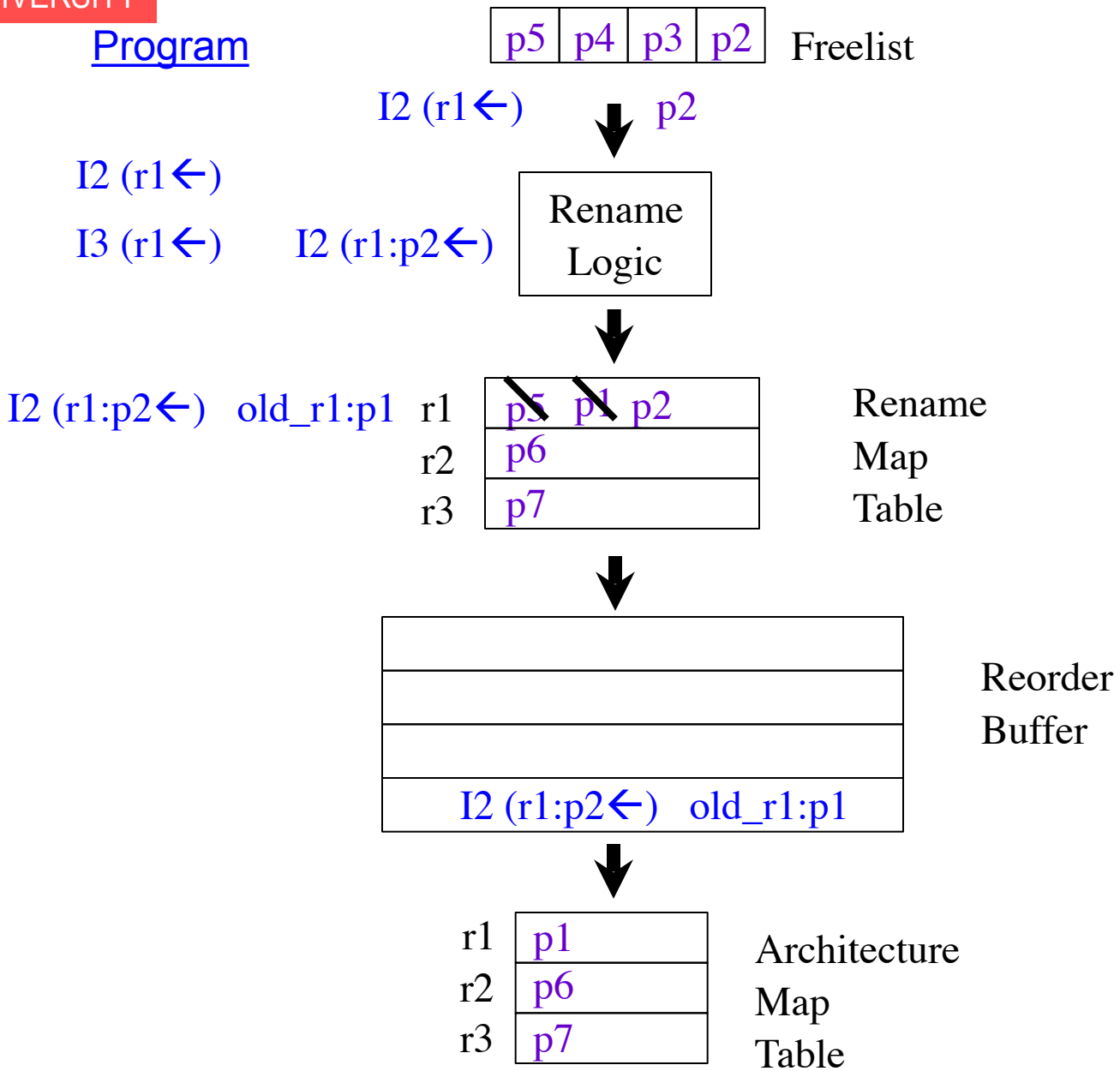
Spectrum of fault checks



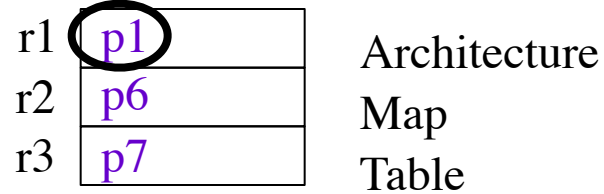
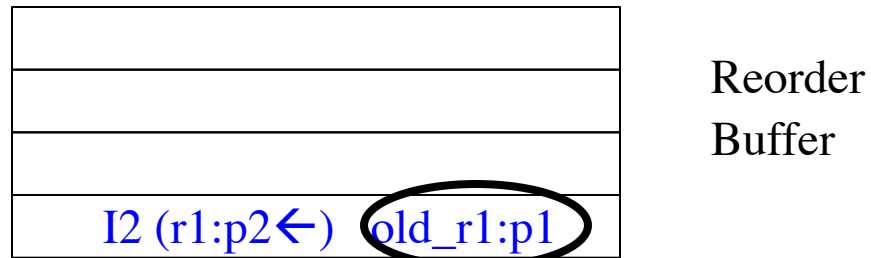
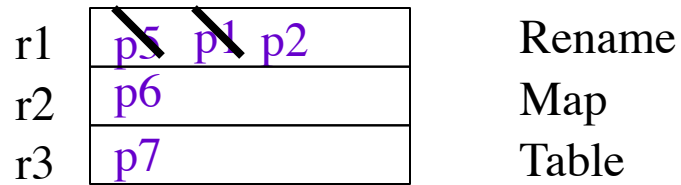
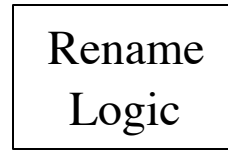
Examples of Microarchitectural Assertions

- Register Name Authentication (RNA)
 - Aims to detect faults in renaming unit
 - Asserts consistencies in renaming unit
 - Exploits inherent redundancy in renaming structures
 - Asserts expected physical register states
- Timestamp-based Assertion Checking (TAC)
 - Aims to detect faults in issue unit
 - Asserts sequential order among data dependent instructions
 - Uses timestamps





Program

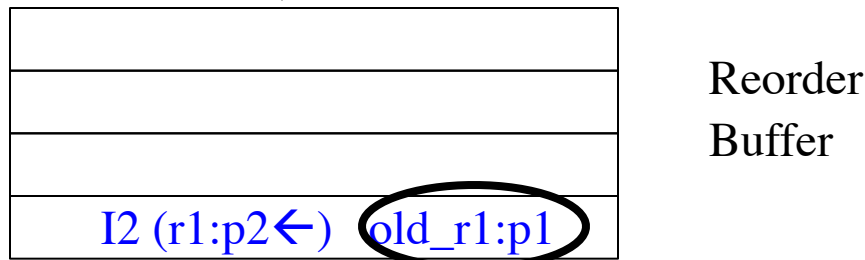
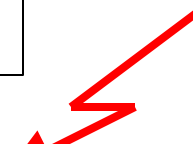
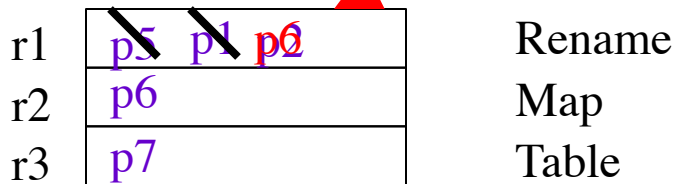
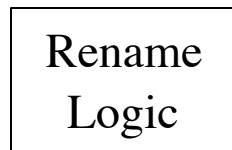
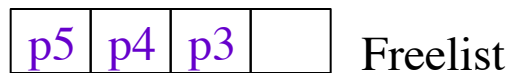


I3 (r1←)

Observation

r1's old == r1's arch
mapping == r1's arch
mapping

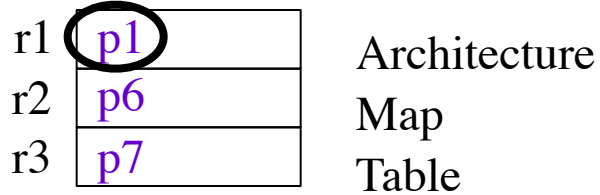
Program



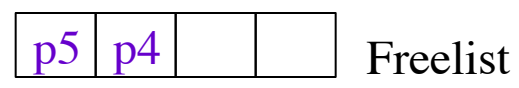
RNA prev mapping check

old_r1 == arch_r1?

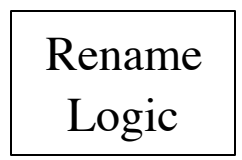
p1 == p1?



Program

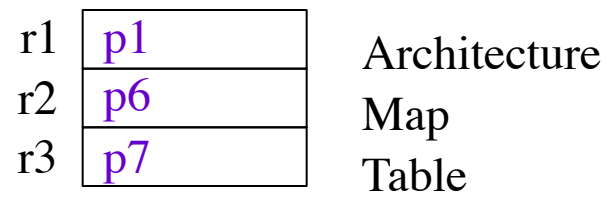
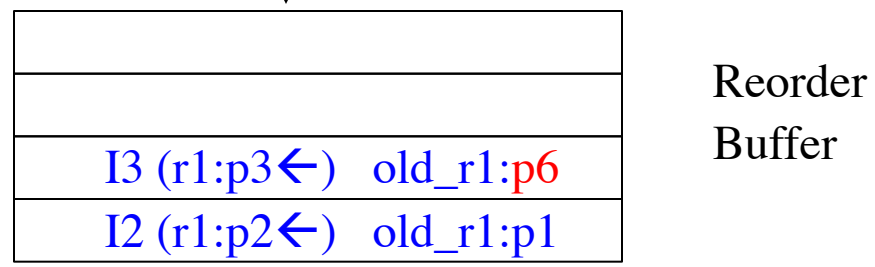
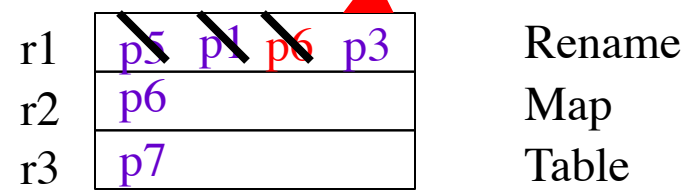


I3 (r1 ←) p3

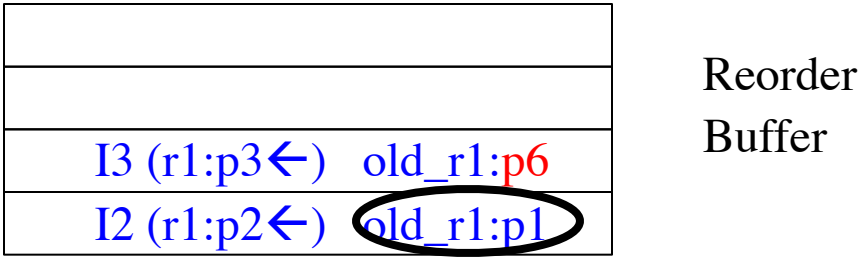
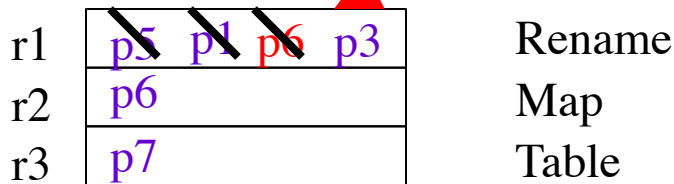
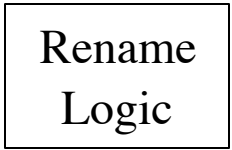


I3 (r1:p3 ←)

I3 (r1:p3 ←) old_r1:p6



Program

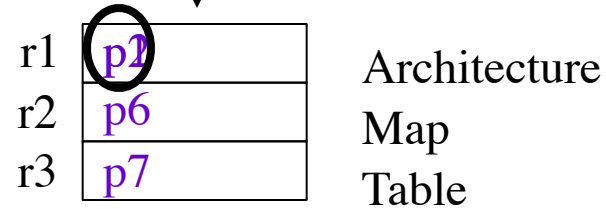


RNA prev mapping check

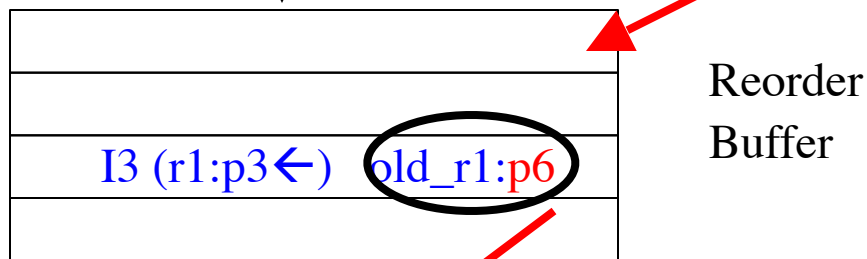
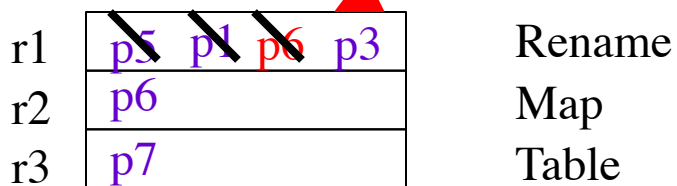
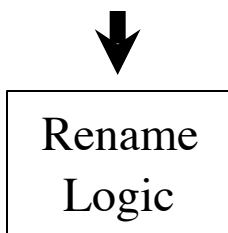
old_r1 == arch_r1?

p1 == p1?

I2 retires



Program



RNA prev mapping check

old_r1 == arch_r1?

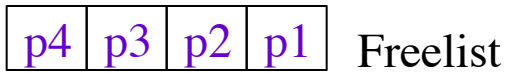
p6 == p2?

FAULT DETECTED



At I3 retirement

Program

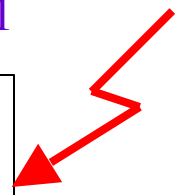
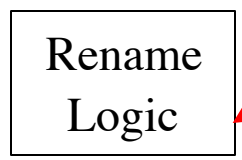


I1 (r1 ←)

I1 (r1 ←) p1

I2 (r1 ←)

I1 (r1:p6 ←)

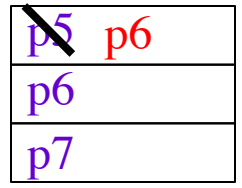


I1 (r1:p6 ←)

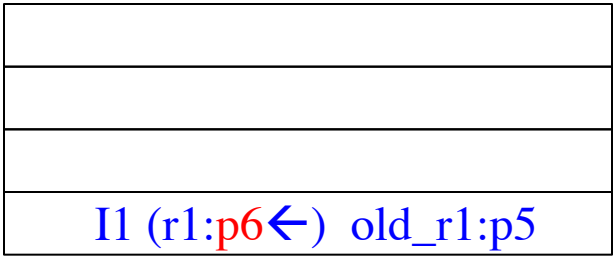
old_r1:p5

r2

r3



Rename
Map
Table

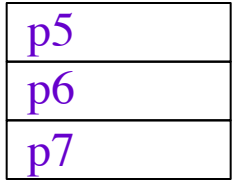


Reorder
Buffer

r1

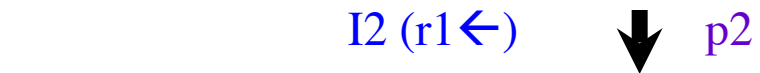
r2

r3



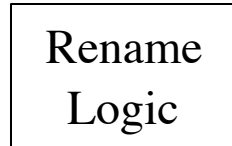
Architecture
Map
Table

Program



I2 (r1 ←)

I2 (r1:p2 ←)

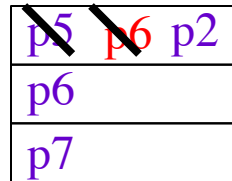


I2 (r1:p2 ←)

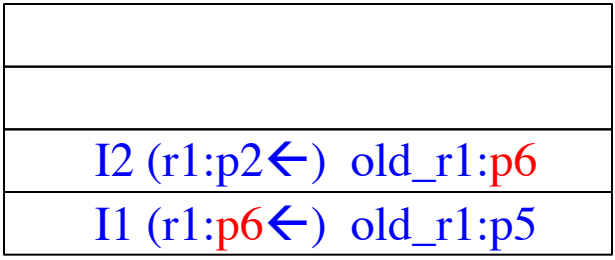
old_r1:p6

r2

r3



Rename
Map
Table

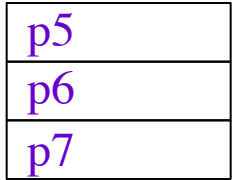


Reorder
Buffer

r1

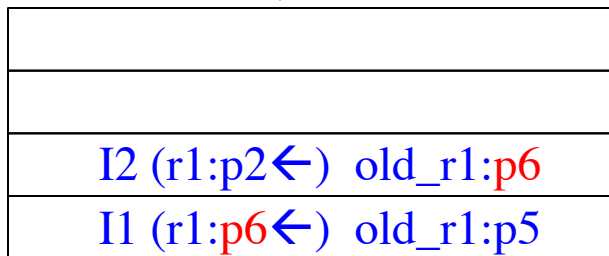
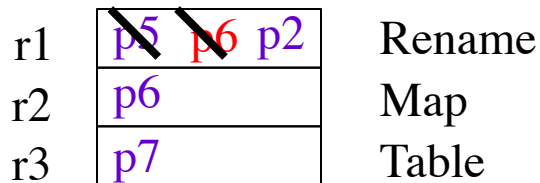
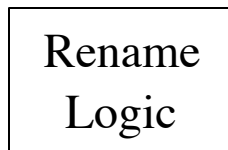
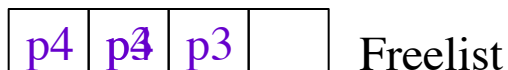
r2

r3



Architecture
Map
Table

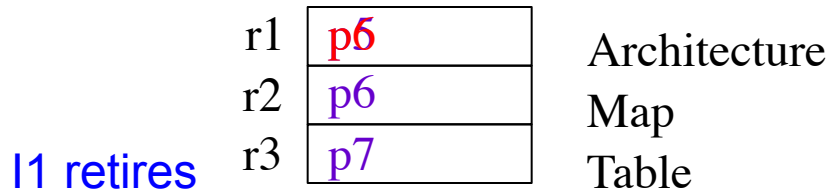
Program



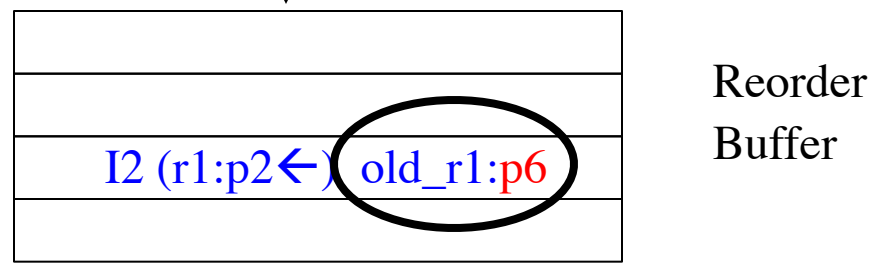
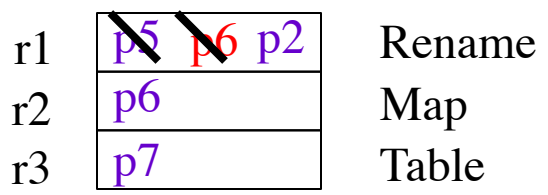
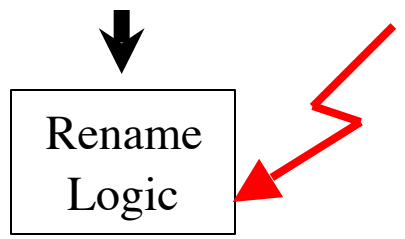
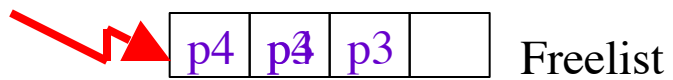
RNA prev mapping check

old_r1 == arch_r1?

p5 == p5?



Program



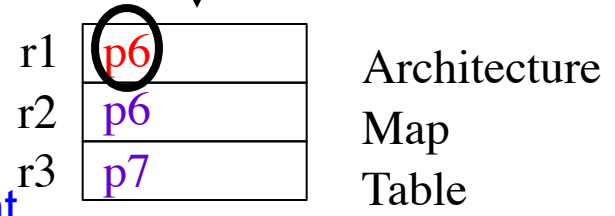
RNA prev mapping check

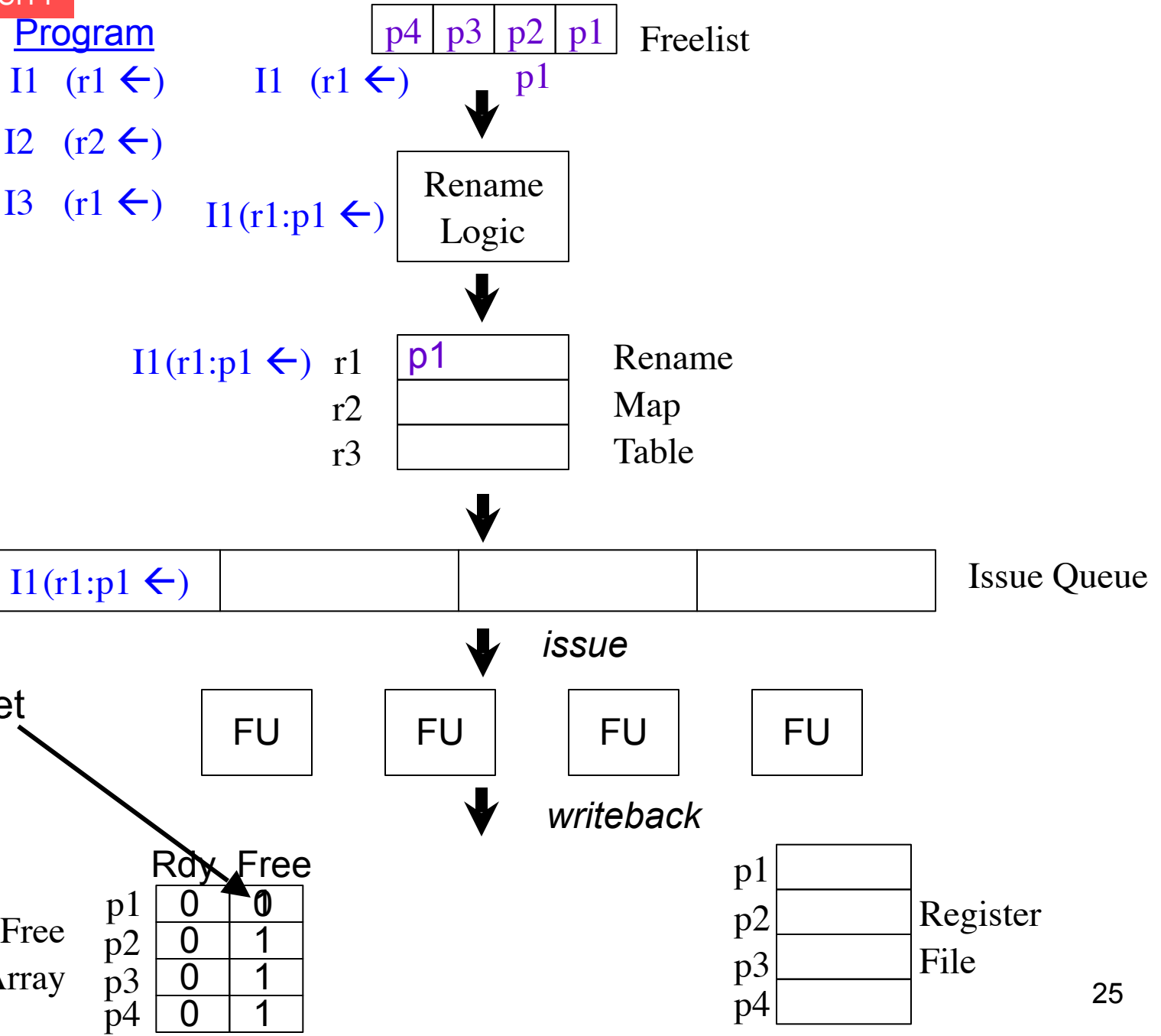
old_r1 == arch_r1?

p6 == p6?

FAULT NOT DETECTED

At I2 retirement





Program



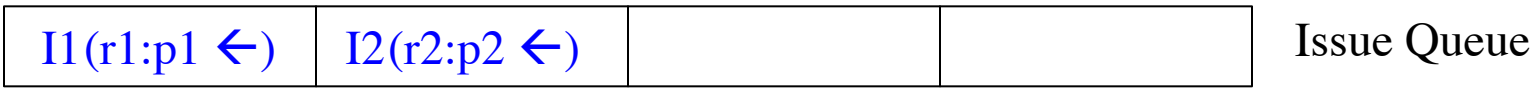
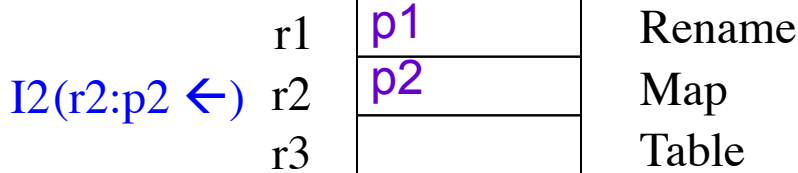
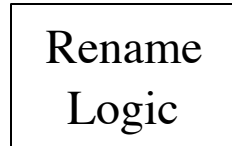
I2 (r2 ←) p2



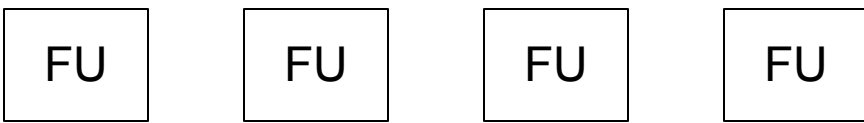
I2 (r2 ←)

I3 (r1 ←)

I2(r2:p2 ←)



issue



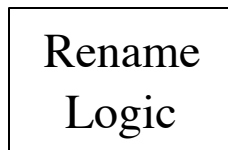
writeback

Rdy/Free Bit Array

	Rdy	Free
p1	0	0
p2	0	0
p3	0	1
p4	0	1

p1		Register File
p2		
p3		
p4		

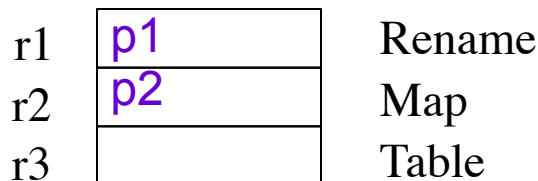
Program



I3 (r1 ←)
Observation

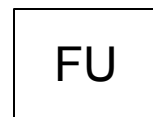
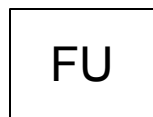
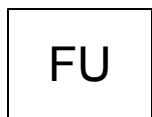
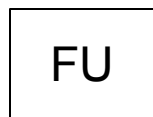
Ready bit == 0 (not executed)

Free bit == 0 (not in freelist)



issue

Ready bit set



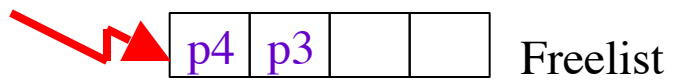
writeback

Rdy/Free Bit Array

	Rdy	Free
p1	0	0
p2	0	0
p3	0	1
p4	0	1

p1	XXX	Register File
p2	XXX	
p3		
p4		

Program



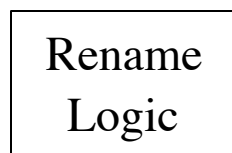
I3 (r1 ←)



RNA writeback check

I3 (r1 ←)

I3(r1:p2 ←)



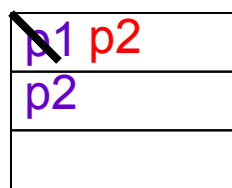
Free of p2 == 0? ✓

Ready of p2 == 0? ✗

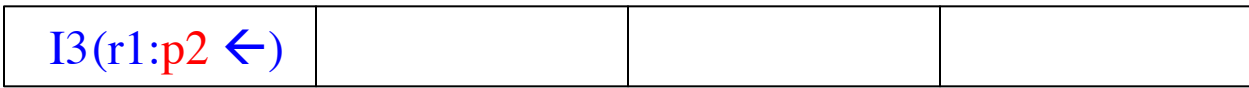
FAULT DETECTED

I3(r1:p2 ←)

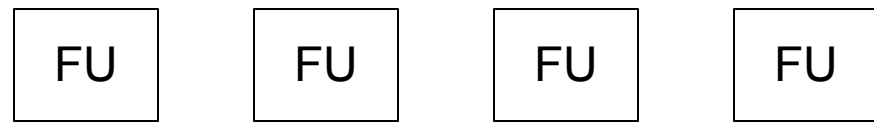
r1
r2
r3



Rename Map Table



issue



writeback

Rdy/Free Bit Array

	Rdy	Free
p1	1	0
p2	1	0
p3	0	0
p4	0	1

p1	XXX
p2	XXX
p3	
p4	

Register File

RNA summary

- RNA previous mapping check
 - Detects faults in renaming structures
 - Rename map table, Architecture map table
 - Branch checkpoint tables
 - Active list (renaming state)
- RNA writeback state check
 - Detects faults in renaming logic and freelist

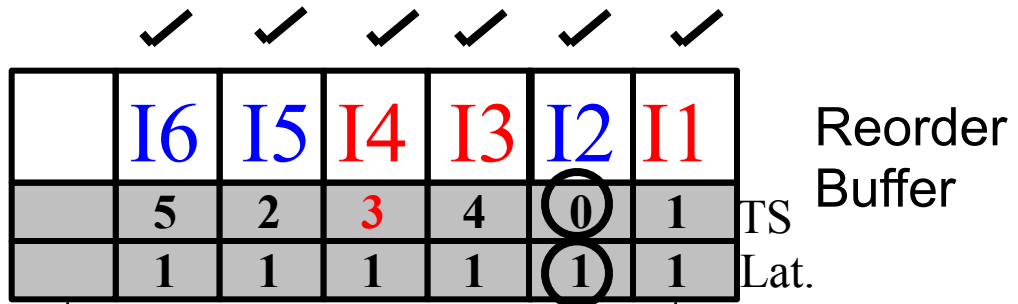
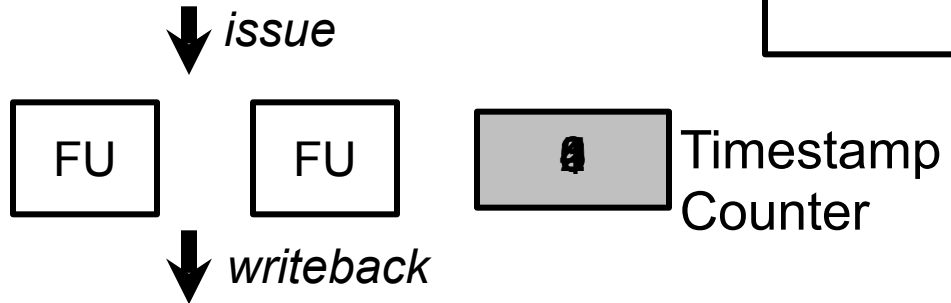
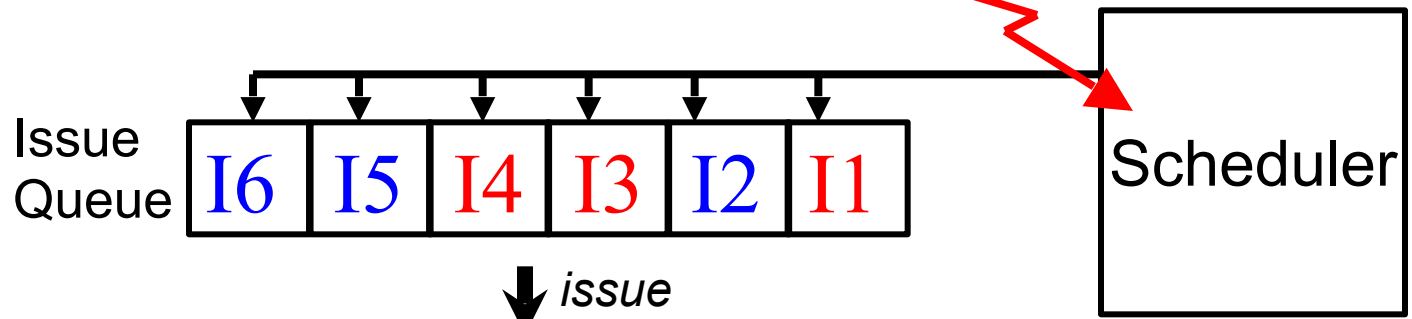
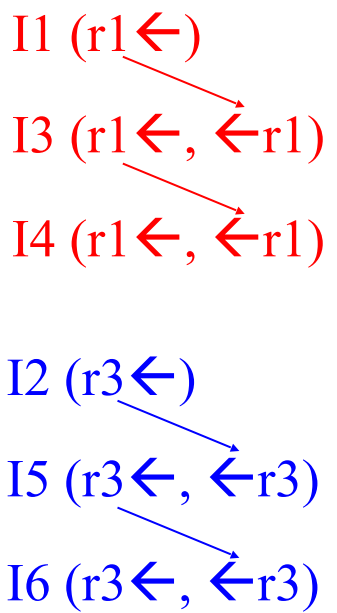
Source renaming

- Pure source renaming faults undetected
 - E.g., fault in source renaming logic
 - Researching solutions similar to RNA
- However, faults causing deadlock are detectable
 - Faulty source name causing cyclic dependency
 - Faulty source name points to unpopped freelist entry
 - Other faults that cause phantom producers
- Use watchdog timer to detect deadlocks

Timestamp-based Assertion Checking (TAC)

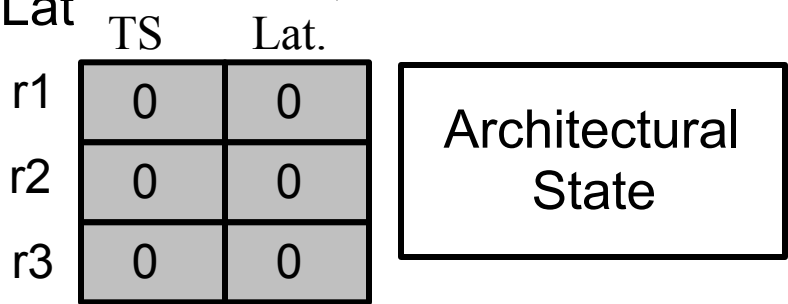
- Confirm data dependent instructions issued sequentially
 - Assign timestamps to instructions at issue
 - At retirement, confirm instruction timestamp greater than producers' timestamps
- TAC check
 - Instruction timestamp \geq Producer's timestamp + latency
- Faults on checking logic can only cause false alarms

Dataflow



TAC check

$\text{Instr TS} \geq \text{Prod TS} + \text{Prod Lat}$



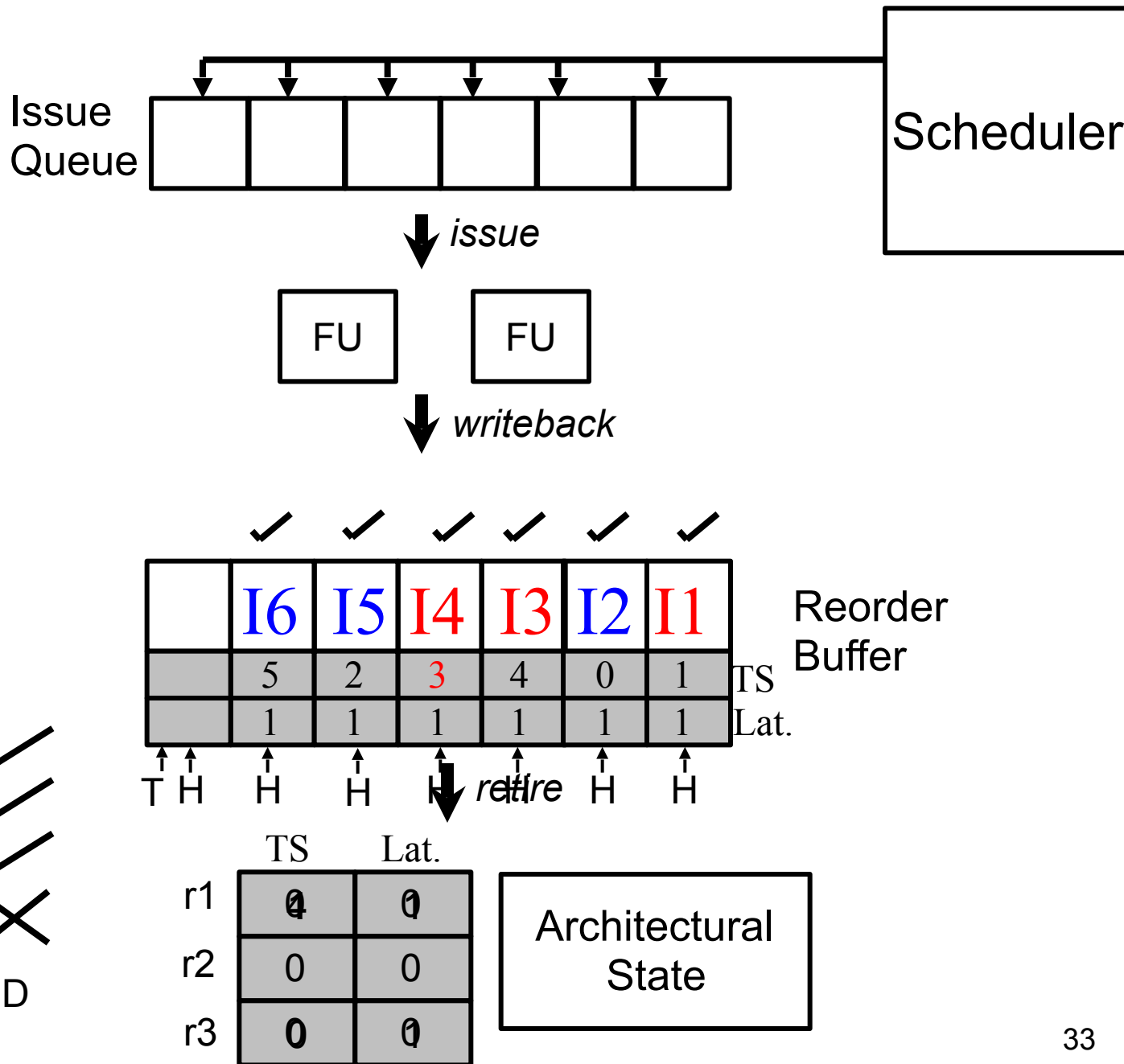
Dataflow

I1 (r1 ←)
 I3 (r1 ←, ←r1)
 I4 (r1 ←, ←r1)
 I2 (r3 ←)
 I5 (r3 ←, ←r3)
 I6 (r3 ←, ←r3)

TAC check

I1: $1 \geq 0 + 0$ ✓
 I2: $0 \geq 0 + 0$ ✓
 I3: $4 \geq 1 + 1$ ✓
 I4: $3 \geq 4 + 1$ ✗

FAULT DETECTED



Experiments

- Randomly injected faults in timing simulator
 - 1000 faults per benchmark
 - Faults target issue and rename state
 - Simulation ends 1 million cycles following fault injection
- Observations
 - Fault detected by an assert (Assert) or not (Undet)
 - Fault corrupts architectural state (SDC) or not (Masked)
- Possible outcomes
 - Assert+SDC
 - Undet+SDC
 - Assert+Masked
 - Undet+Masked

TAC - Fault Injection Experiments

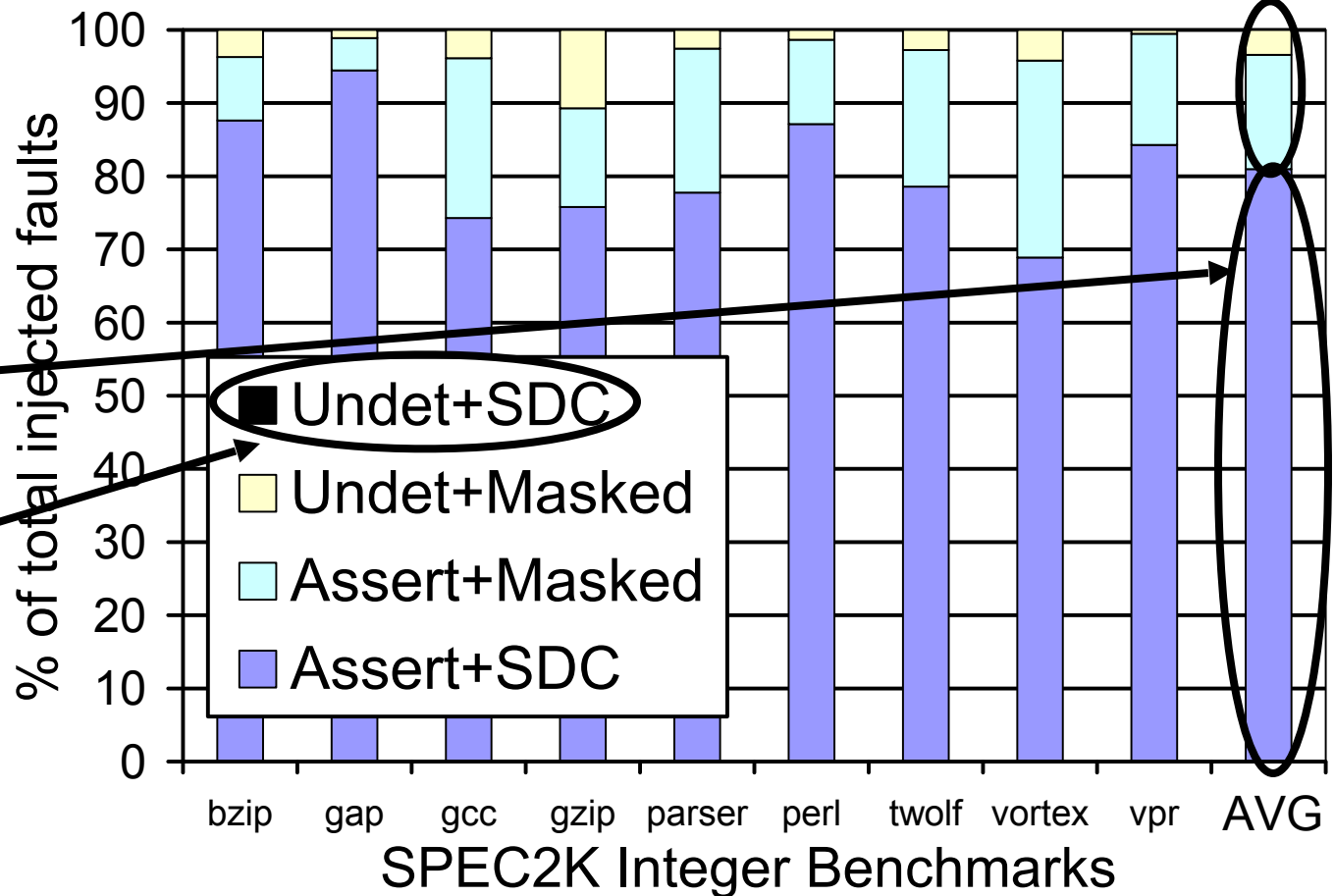
- Type of faults injected
 - Ready bits prematurely set
 - Speculatively issued cache-missing load dependents not reissued

TAC - Fault Injection Experiments

80% of faults cause SDC
 20% of faults are masked

All SDC faults are detected

Zero undetected SDC faults



RNA - Fault Injection Experiments

- Faults injected
 - Flip bits of an entry in architecture map table
 - Flip bits of an entry in rename map table
 - Flip bits of an entry in freelist
 - Flip destination register bits at dispatch
- Watchdog timer included to detect deadlocks
- Additional possible outcomes
 - Assert+Wdog : RNA detected a future deadlock
 - Undet+Wdog : Deadlock undetected by RNA (possibly would have been caught by RNA in future)

RNA - Fault Injection Experiments

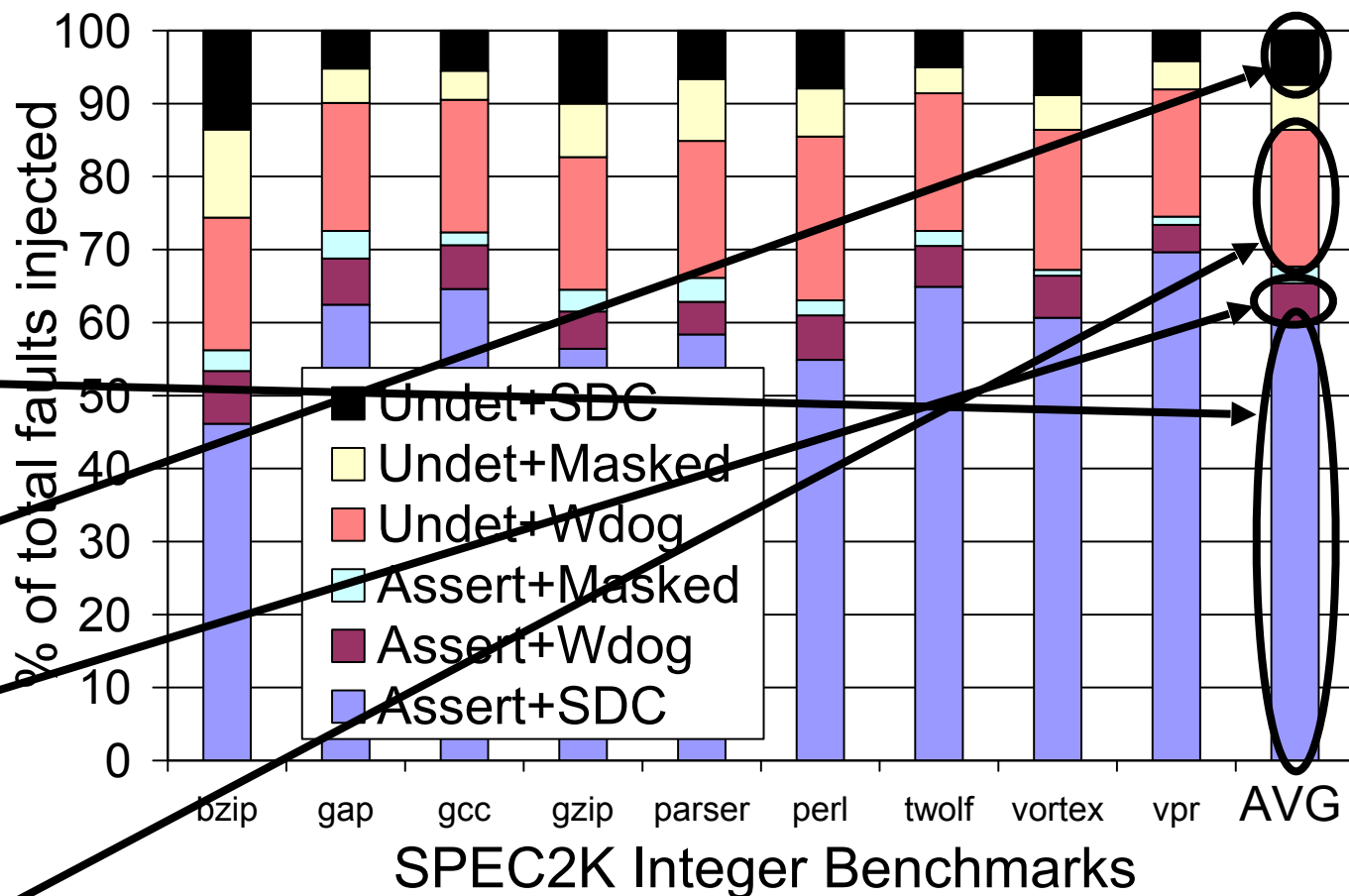
68% SDC faults
24% deadlocks
8% masked faults

88% of SDC faults
detected by RNA

12% of SDC faults
undetected

25% of deadlocks
detected by RNA
beforehand

75% of deadlocks
not detected by RNA
(but detected by
watchdog)



RNA - Fault outcome distribution

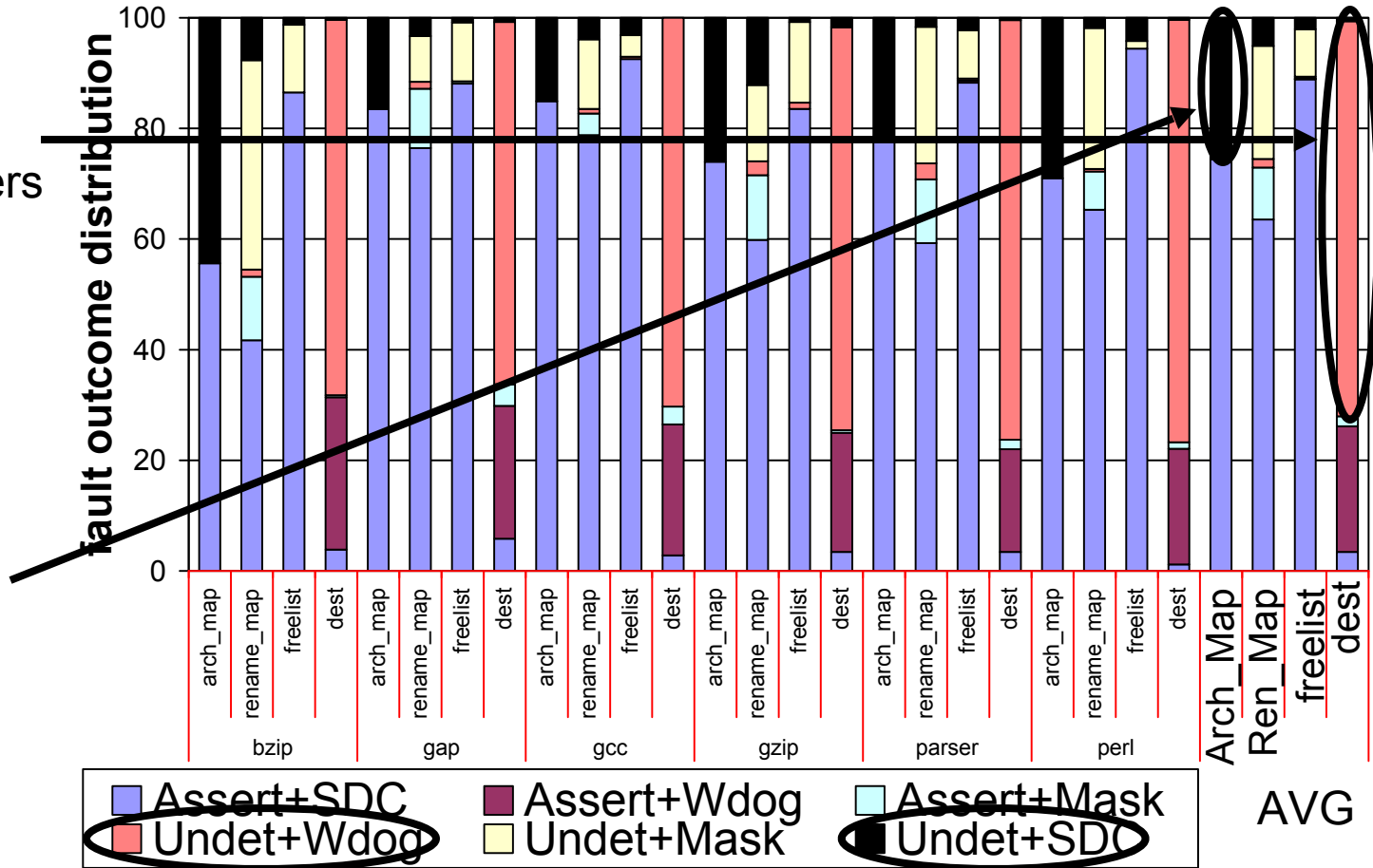
“dest” faults cause deadlocks because of phantom producers

Deadlock blocks retirement
Thus, RNA check can't complete

“arch_map” faults cause most undetected SDC

Long live register range

System trap before RNA check can complete



Conclusions

